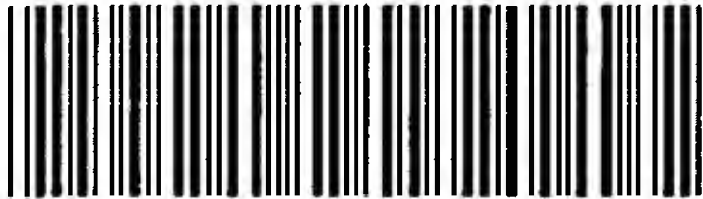


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/604,796	CHANG ET AL.	
	Examiner	Art Unit	
	Hashem Farrokh	2187	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
711	167	1/19/2005	HF
710	57	1/19/2005	HF

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
PALM and East Inventor Search conducted	1/20/2006	HF
IEEE Xplore Search conducted	1/20/2006	HF
Nasser Moazzami Consulted	1/19/2006	HF
EAST (PGPUB,USPAT,USOCR,EPO,JPO,D,ERWENT,IBM_TDB)	1/19/2006	HF
711/1-3,101-105,111-115,167; 712/1,38,43 (Text Search updated)	1/20/2006	HF
711/ALL; 370/235,328,382,386,389,392,400,46 6 Text Search see East Prinou	1/19/2006	HF
710/57-60 (Text Search see Printout)	1/19/2006	HF